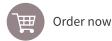


## General purpose LNA MMIC with integrated ESD protection and active biasing









# **Product description**

The BGB707L7ESD is a high performance low noise amplifier (LNA) MMIC based on Infineon's silicon germanium carbon (SiGe:C) bipolar technology.



### **Feature list**

- Minimum noise figure NF<sub>min</sub> = 0.6 dB at 2.4 GHz, 3 V, 3 mA
- Supply voltage  $V_{CC}$  = 1.8 V to 4.0 V at  $T_A$  = 25 °C
- Integrated ESD protection: 2 kV HBM at all pins

### **Product validation**

Qualified for industrial applications according to the relevant tests of JEDEC47/20/22.

## **Potential applications**

- Satellite navigation systems (e.g. GPS, GLONASS, BeiDou, Galileo)
- Wireless communications: WLAN 2.4 GHz and 5-6 GHz bands, broadband LTE or WiMAX LNA
- ISM applications like RKE and smart meter, as well as for emerging wireless applications such as DVB-Terrestrial

## **Device information**

#### Table 1 Part information

Product name / Ordering code	Package	Pin configu	Pin configuration						
BGB707L7ESD /	TSLP-7-1	1 = V <sub>CC</sub>	$2 = V_{\text{Bias}}$	$3 = RF_{in}$	$4 = RF_{\text{out}}$	AZ	7500		
BGB707L7ESDE6327XTSA1		$5 = V_{\text{Ctrl}}$	6 = Current adjust	7 = Ground					

Attention: ESD (Electrostatic discharge) sensitive device, observe handling precautions

### General purpose LNA MMIC with integrated ESD protection and active biasing



**Functional block diagram** 

# **Functional block diagram**

This functional block diagram explains how the BGB707L7ESD is used. The RF power on/off function is controlled by applying  $V_{\rm Ctrl}$ . By using an external resistor  $R_{\rm ext}$ , the pre-set current of 2.1 mA (when  $R_{\rm ext}$  is omitted) can be increased. Base  $V_{\rm B}$  and collector  $V_{\rm C}$  voltages are applied to the respective pins  $RF_{\rm in}$  and  $RF_{\rm out}$  by external inductors  $L_{\rm B}$  and  $L_{\rm C}$ .

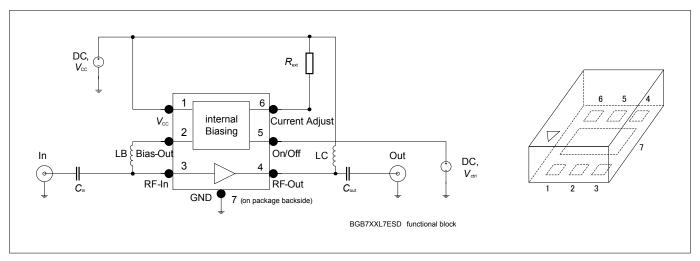


Figure 1 Functional block diagram

## General purpose LNA MMIC with integrated ESD protection and active biasing



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### General purpose LNA MMIC with integrated ESD protection and active biasing



**Operating conditions** 

# **1** Operating conditions

Table 2 Operation conditions at  $T_A = 25$  °C

Parameter	Symbol		Values		Unit	Note or test condition
		Min.	Тур.	Max.		
Supply voltage	V <sub>CC</sub>	1.8	3	4	V	_
Control voltage in on-mode	V <sub>Ctrl-on</sub>	1.2	_	V <sub>CC</sub>		
Control voltage in off-mode	$V_{Ctrl-off}$	-0.3		0.3		

# 2 Absolute maximum ratings

Table 3 Absolute maximum ratings at  $T_A = 25$  °C (unless otherwise specified)

Parameter	Symbol	Va	Values		Note or test condition	
		Min.	Max.			
Supply voltage	$V_{CC}$	_	4	V	T <sub>A</sub> = 25 °C	
			3.5		T <sub>A</sub> = -55 °C	
Supply current	I <sub>CC</sub>		25	mA	-	
DC current at <i>RF</i> <sub>in</sub>	I <sub>B</sub>		2			
Control voltage	$V_{Ctrl}$		4	V		
Total power dissipation <sup>1)</sup>	P <sub>tot</sub>		100	mW	<i>T</i> <sub>S</sub> ≤ 112 °C	
Junction temperature	TJ		150	°C	-	
Storage temperature	$T_{Stg}$	-55				

Attention: Stresses above the max. values listed here may cause permanent damage to the device.

Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Exceeding only one of these values may cause irreversible damage to the integrated circuit.

 $T_S$  is the soldering point temperature.  $T_S$  is measured on the emitter lead at the soldering point of the PCB.

## General purpose LNA MMIC with integrated ESD protection and active biasing



Thermal characteristics

# **3** Thermal characteristics

Table 4 Thermal resistance

Parameter	Symbol		Values		Unit Note or test condition	
		Min.	Тур.	Max.		
Junction - soldering point	R <sub>thJS</sub>	_	375	_	K/W	-

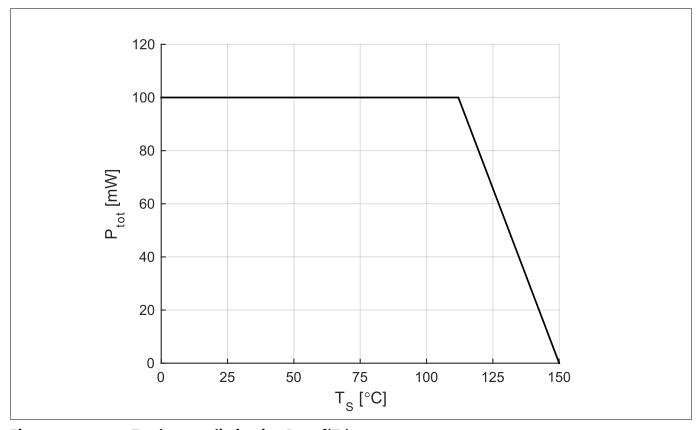


Figure 2 Total power dissipation  $P_{\text{tot}} = f(T_S)$ 

## General purpose LNA MMIC with integrated ESD protection and active biasing



### **Electrical characteristics**

# **4** Electrical characteristics

## 4.1 DC characteristics

Table 5 DC characteristics at  $V_{CC} = 3 \text{ V}$ ,  $T_A = 25 ^{\circ}\text{C}$ 

Parameter	Symbol		Values		Unit	Note or test
		Min.	Тур.	Max.		condition
Supply current in on-mode	I <sub>CC-on</sub>				mA	<i>V</i> <sub>Ctrl</sub> = 3 V
		1.6	2.1	2.6		$R_{\rm ext}$ = open
		_	3	_		$R_{\rm ext} = 12 \text{ k}\Omega$
		_	4.2	_		$R_{\rm ext} = 4.7 \text{ k}\Omega$
		_	6	_		$R_{\rm ext} = 2.4 \text{ k}\Omega$
		_	10	-		$R_{\rm ext} = 1  \rm k\Omega$
Supply current in off-mode	I <sub>CC-off</sub>	_	-	6	μΑ	V <sub>Ctrl</sub> = 0 V
Control current in on-mode	I <sub>Ctrl-on</sub>		14	20		V <sub>Ctrl</sub> = 3 V
Control current in off-mode	/ <sub>Ctrl-off</sub>		_	0.1		V <sub>Ctrl</sub> = 0 V



#### **Electrical characteristics**

## 4.2 Characteristic DC diagrams

The measurement setup is an application circuit according to *Figure 1* on page 2, using the integrated biasing.  $T_A = 25$  °C (unless otherwise specified).

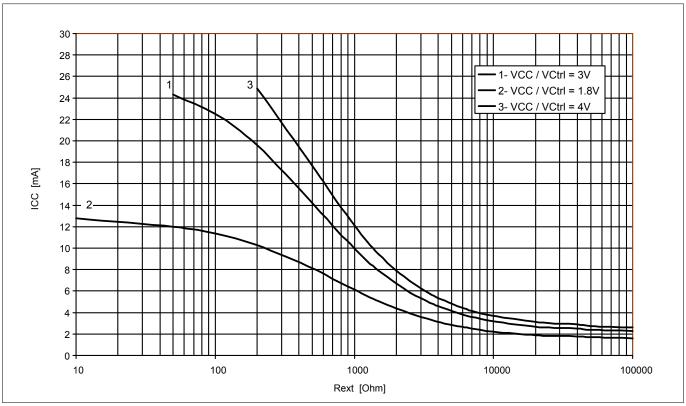


Figure 3 Supply current vs external resistance  $I_{CC} = f(R_{ext})$ ,  $V_{CC} / V_{Ctrl} = parameter$ 

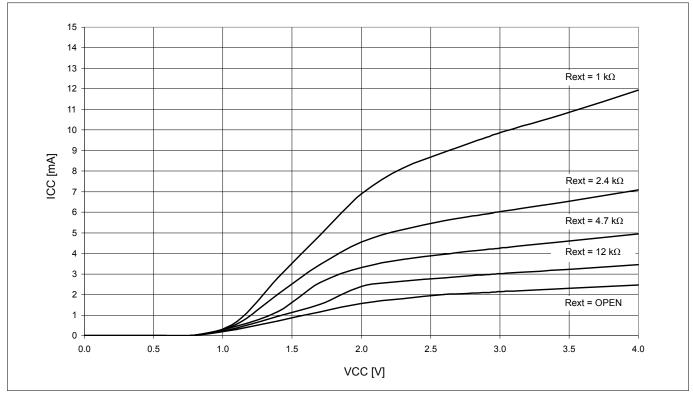


Figure 4 Supply current vs supply voltage  $I_{CC} = f(V_{CC})$ ,  $V_{Ctrl} = 3 \text{ V}$ ,  $R_{ext} = \text{parameter}$ 

## General purpose LNA MMIC with integrated ESD protection and active biasing



v4.0

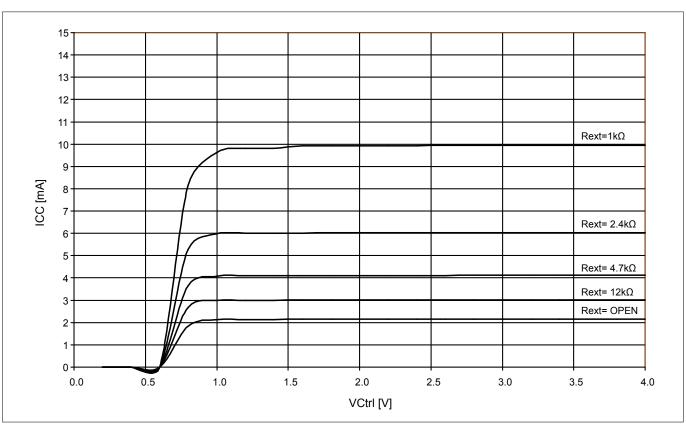
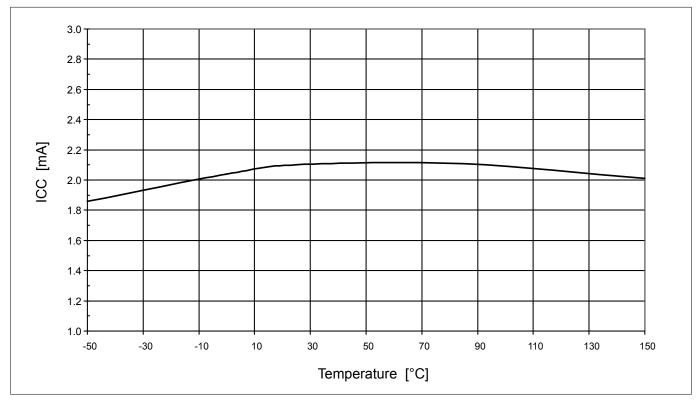


Figure 5 Supply current vs control voltage  $I_{CC} = f(V_{Ctrl})$ ,  $V_{CC} = 3 \text{ V}$ ,  $R_{ext} = \text{parameter}$ 



Supply current vs temperature  $I_{CC} = f(T_A)$ ,  $V_{Ctrl} = V_{CC} = 3 \text{ V}$ ,  $R_{ext} = \text{open}$ Figure 6

### General purpose LNA MMIC with integrated ESD protection and active biasing



#### **Electrical characteristics**

### 4.3 AC characteristics

AC characteristics are described for higher frequencies in a 50  $\Omega$  environment.

### 4.3.1 AC characteristics in test fixture

Measurement setup is a test fixture with Bias-T's in a 50  $\Omega$  system according to *Figure 7*, for frequencies f from 150 MHz to 10 GHz at  $V_C$  = 3 V,  $T_A$  = 25 °C. The collector current  $I_C$  is controlled by the external base voltage  $V_B$ . Which is not dependent of the biasing reference voltage  $V_{Bias}$ . The bias voltage  $V_C$  at the output  $RF_{out}$  allows direct measurement of the amplifier performance, as a function of bias conditions without passive components.

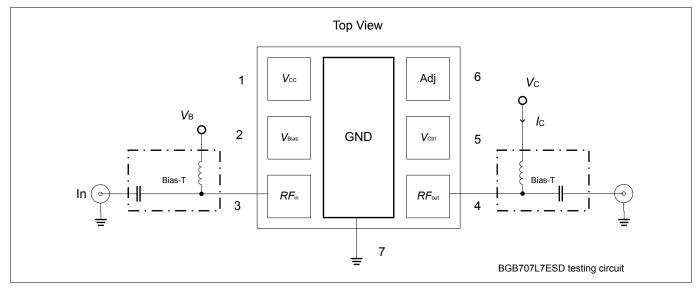


Figure 7 Testing circuit for frequencies f from 150 MHz to 10 GHz

### General purpose LNA MMIC with integrated ESD protection and active biasing



Table 6 AC characteristics,  $V_C = 3 \text{ V}$ , f = 150 MHz

Parameter	Symbol	Values			Unit	Note or test conditions	
		Min.	Тур.	Max.	7		
Minimum noise figure	NF <sub>min</sub>	_	0.4	_	dB	I <sub>C</sub> = 2.1 mA	
			0.4			$I_{\rm C} = 3  \rm mA$	
			0.5			$I_{C} = 6 \text{ mA}$	
			0.55			I <sub>C</sub> = 10 mA	
Transducer gain	$ S_{21} ^2$		17			I <sub>C</sub> = 2.1 mA	
			19			$I_C = 3 \text{ mA}$	
			24			$I_{\rm C} = 6  \text{mA}$	
			27			$I_{\rm C}$ = 10 mA	
Maximum power gain	G <sub>ms</sub>		31.5			$I_{\rm C} = 2.1  {\rm mA}$	
			33			$I_C = 3 \text{ mA}$	
			35			$I_C = 6 \text{ mA}$	
			37			$I_{\rm C}$ = 10 mA	
Output 1 dB gain compression	OP <sub>1dB</sub>		3.5		dBm	$I_{Cq} = 2.1 \text{ mA}, I_{Ccomp} = 11 \text{ mA}$	
point <sup>1)</sup>			4			$I_{Cq} = 3 \text{ mA}, I_{Ccomp} = 11 \text{ mA}$	
			4.5			$I_{Cq} = 6 \text{ mA}, I_{Ccomp} = 11 \text{ mA}$	
			3			$I_{Cq} = 10 \text{ mA}, I_{Ccomp} = 11 \text{ mA}$	
Output 3 <sup>rd</sup> order intercept point	OIP <sub>3</sub>		2	1		I <sub>C</sub> = 2.1 mA	
			6			$I_{\rm C} = 3  \text{mA}$	
			14.5			$I_{\rm C} = 6  \text{mA}$	
			19.5			I <sub>C</sub> = 10 mA	

 $<sup>^{1}</sup>$  OP<sub>1dB</sub> is the output compression point achieved in a 50 Ω application circuit according to **Figure 1** using the integrated biasing.

 $I_{Cq}$  is the quiescent current at small input power levels.  $I_{Cq}$  increases up to  $I_{Ccomp}$  as RF input power approaches  $IP_{1dB}$ , cf. *Figure 14*.

### General purpose LNA MMIC with integrated ESD protection and active biasing



Table 7 AC characteristics,  $V_C = 3 \text{ V}$ , f = 450 MHz

Parameter	Symbol	Values			Unit	Note or test conditions	
		Min.	Тур.	Max.			
Minimum noise figure	NF <sub>min</sub>	_	0.45	_	dB	I <sub>C</sub> = 2.1 mA	
			0.45			$I_{\rm C} = 3  \rm mA$	
			0.5			$I_{\rm C} = 6  \text{mA}$	
			0.6			I <sub>C</sub> = 10 mA	
Transducer gain	$ S_{21} ^2$		17			I <sub>C</sub> = 2.1 mA	
			19			$I_C = 3 \text{ mA}$	
			24			$I_{\rm C}$ = 6 mA	
			27			$I_{\rm C}$ = 10 mA	
Maximum power gain	G <sub>ms</sub>		27			I <sub>C</sub> = 2.1 mA	
			28			$I_{\rm C} = 3  \text{mA}$	
			30.5			$I_C = 6 \text{ mA}$	
			32			$I_{\rm C}$ = 10 mA	
Output 1 dB gain compression	OP <sub>1dB</sub>		11.5		dBm	$I_{Cq} = 2.1 \text{ mA}, I_{Ccomp} = 11 \text{ mA}$	
point <sup>1)</sup>			12			$I_{Cq} = 3 \text{ mA}, I_{Ccomp} = 14 \text{ mA}$	
			11.5			$I_{Cq} = 6 \text{ mA}, I_{Ccomp} = 16 \text{ mA}$	
			9.5			$I_{Cq} = 10 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$	
Output 3 <sup>rd</sup> order intercept point	OIP <sub>3</sub>		2			I <sub>C</sub> = 2.1 mA	
			5.5			$I_{\rm C} = 3  \text{mA}$	
			14			$I_{\rm C} = 6  \text{mA}$	
			19.5			I <sub>C</sub> = 10 mA	

 $<sup>^{1}</sup>$  OP<sub>1dB</sub> is the output compression point achieved in a 50 Ω application circuit according to **Figure 1** using the integrated biasing.

 $I_{Cq}$  is the quiescent current at small input power levels.  $I_{Cq}$  increases up to  $I_{Ccomp}$  as RF input power approaches  $IP_{1dB}$ , cf. *Figure 14*.

### General purpose LNA MMIC with integrated ESD protection and active biasing



Table 8 AC characteristics,  $V_C = 3 \text{ V}$ , f = 900 MHz

Parameter	Symbol	Values			Unit	Note or test conditions	
		Min.	Тур.	Max.			
Minimum noise figure	NF <sub>min</sub>	_	0.55	_	dB	I <sub>C</sub> = 2.1 mA	
			0.55			$I_{\rm C} = 3  \rm mA$	
			0.6			$I_{\rm C} = 6  \text{mA}$	
			0.7			I <sub>C</sub> = 10 mA	
Transducer gain	$ S_{21} ^2$		17			I <sub>C</sub> = 2.1 mA	
			19			$I_C = 3 \text{ mA}$	
			23.5			$I_{\rm C}$ = 6 mA	
			26			$I_{\rm C} = 10  {\rm mA}$	
Maximum power gain	G <sub>ms</sub>		24			I <sub>C</sub> = 2.1 mA	
			25			$I_{\rm C} = 3  \text{mA}$	
			27.5			$I_C = 6 \text{ mA}$	
			29			$I_{\rm C}$ = 10 mA	
Output 1 dB gain compression	OP <sub>1dB</sub>		11		dBm	$I_{Cq} = 2.1 \text{ mA}, I_{Ccomp} = 13 \text{ mA}$	
point <sup>1)</sup>			11			$I_{Cq} = 3 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$	
			10			$I_{Cq} = 6 \text{ mA}, I_{Ccomp} = 14 \text{ mA}$	
			8.5			$I_{Cq} = 10 \text{ mA}, I_{Ccomp} = 14 \text{ mA}$	
Output 3 <sup>rd</sup> order intercept point	OIP <sub>3</sub>		3.5			I <sub>C</sub> = 2.1 mA	
			8			$I_{\rm C} = 3  \text{mA}$	
			17			$I_{\rm C} = 6  \text{mA}$	
			19.5			I <sub>C</sub> = 10 mA	

 $<sup>^{1}</sup>$  OP<sub>1dB</sub> is the output compression point achieved in a 50 Ω application circuit according to **Figure 1** using the integrated biasing.

 $I_{Cq}$  is the quiescent current at small input power levels.  $I_{Cq}$  increases up to  $I_{Ccomp}$  as RF input power approaches  $IP_{1dB}$ , cf. *Figure 14*.

### General purpose LNA MMIC with integrated ESD protection and active biasing



Table 9 AC characteristics,  $V_C = 3 \text{ V}, f = 1.5 \text{ GHz}$ 

Parameter	Symbol	Values			Unit	Note or test conditions	
		Min.	Тур.	Мах.			
Minimum noise figure	NF <sub>min</sub>	_	0.6	_	dB	I <sub>C</sub> = 2.1 mA	
			0.6			$I_{\rm C}$ = 3 mA	
			0.6			$I_C = 6 \text{ mA}$	
			0.7			$I_{\rm C}$ = 10 mA	
Transducer gain	$ S_{21} ^2$		16			I <sub>C</sub> = 2.1 mA	
			18.5			$I_C = 3 \text{ mA}$	
			22.5			$I_{C} = 6 \text{ mA}$	
			24.5			$I_{\rm C}$ = 10 mA	
Maximum power gain	G <sub>ms</sub>		21.5			I <sub>C</sub> = 2.1 mA	
			23			$I_{\rm C}$ = 3 mA	
			25.5			$I_C = 6 \text{ mA}$	
			27			$I_{\rm C} = 10  {\rm mA}$	
Output 1 dB gain compression	OP <sub>1dB</sub>		10.5		dBm	$I_{Cq} = 2.1 \text{ mA}, I_{Ccomp} = 14 \text{ mA}$	
point <sup>1)</sup>			10			$I_{Cq} = 3 \text{ mA}, I_{Ccomp} = 16 \text{ mA}$	
			9			$I_{Cq} = 6 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$	
			8			$I_{Cq} = 10 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$	
Output 3 <sup>rd</sup> order intercept point	OIP <sub>3</sub>		3.5			I <sub>C</sub> = 2.1 mA	
			8			$I_{\rm C} = 3  \text{mA}$	
			17			$I_{\rm C} = 6  \text{mA}$	
			19.5			I <sub>C</sub> = 10 mA	

 $<sup>^{1}</sup>$  OP<sub>1dB</sub> is the output compression point achieved in a 50 Ω application circuit according to **Figure 1** using the integrated biasing.

 $I_{Cq}$  is the quiescent current at small input power levels.  $I_{Cq}$  increases up to  $I_{Ccomp}$  as RF input power approaches  $IP_{1dB}$ , cf. *Figure 14*.

### General purpose LNA MMIC with integrated ESD protection and active biasing



Table 10 AC characteristics,  $V_C = 3 \text{ V}, f = 1.9 \text{ GHz}$ 

Parameter	Symbol	Values			Unit	Note or test conditions	
		Min.	Тур.	Max.			
Minimum noise figure	NF <sub>min</sub>	_	0.6	_	dB	I <sub>C</sub> = 2.1 mA	
			0.6			$I_{\rm C} = 3  \text{mA}$	
			0.6			$I_C = 6 \text{ mA}$	
			0.7			$I_{\rm C}$ = 10 mA	
Transducer gain	$ S_{21} ^2$		16			I <sub>C</sub> = 2.1 mA	
			18			$I_C = 3 \text{ mA}$	
			21.5			$I_{C} = 6 \text{ mA}$	
			23			$I_{\rm C} = 10  {\rm mA}$	
Maximum power gain	G <sub>ms</sub>		21			$I_{\rm C} = 2.1  {\rm mA}$	
			22			$I_C = 3 \text{ mA}$	
			24			$I_C = 6 \text{ mA}$	
			26			$I_{\rm C}$ = 10 mA	
Output 1 dB gain compression	OP <sub>1dB</sub>		10		dBm	$I_{Cq} = 2.1 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$	
point <sup>1)</sup>			10			$I_{Cq} = 3 \text{ mA}, I_{Ccomp} = 16 \text{ mA}$	
			8.5			$I_{Cq} = 6 \text{ mA}, I_{Ccomp} = 14 \text{ mA}$	
			8			$I_{Cq} = 10 \text{ mA}, I_{Ccomp} = 14 \text{ mA}$	
Output 3 <sup>rd</sup> order intercept point	OIP <sub>3</sub>		3.5			I <sub>C</sub> = 2.1 mA	
			7.5			$I_{\rm C} = 3  \text{mA}$	
			17			$I_{\rm C} = 6  \text{mA}$	
			19.5			I <sub>C</sub> = 10 mA	

 $<sup>^{1}</sup>$  OP<sub>1dB</sub> is the output compression point achieved in a 50 Ω application circuit according to **Figure 1** using the integrated biasing.

 $I_{Cq}$  is the quiescent current at small input power levels.  $I_{Cq}$  increases up to  $I_{Ccomp}$  as RF input power approaches  $IP_{1dB}$ , cf. *Figure 14*.

### General purpose LNA MMIC with integrated ESD protection and active biasing



Table 11 AC characteristics,  $V_C = 3 \text{ V}, f = 2.4 \text{ GHz}$ 

Parameter	Symbol	Values			Unit	Note or test conditions	
		Min.	Тур.	Мах.			
Minimum noise figure	NF <sub>min</sub>	_	0.65	_	dB	I <sub>C</sub> = 2.1 mA	
			0.6			$I_{\rm C} = 3  \text{mA}$	
			0.6			$I_{C} = 6 \text{ mA}$	
			0.7			$I_{\rm C}$ = 10 mA	
Transducer gain	$ S_{21} ^2$		15.5			I <sub>C</sub> = 2.1 mA	
			17			$I_C = 3 \text{ mA}$	
			20			$I_{C} = 6 \text{ mA}$	
			21.5			$I_{\rm C}$ = 10 mA	
Maximum power gain	G <sub>ms</sub>		20			I <sub>C</sub> = 2.1 mA	
			21			$I_C = 3 \text{ mA}$	
			23			$I_C = 6 \text{ mA}$	
			25			$I_{\rm C}$ = 10 mA	
Output 1 dB gain compression	OP <sub>1dB</sub>		10		dBm	$I_{\text{Cq}} = 2.1 \text{ mA}, I_{\text{Ccomp}} = 15 \text{ mA}$	
point <sup>1)</sup>			10			$I_{Cq} = 3 \text{ mA}, I_{Ccomp} = 16 \text{ mA}$	
			9			$I_{Cq} = 6 \text{ mA}, I_{Ccomp} = 14 \text{ mA}$	
			8			$I_{Cq} = 10 \text{ mA}, I_{Ccomp} = 14 \text{ mA}$	
Output 3 <sup>rd</sup> order intercept point	OIP <sub>3</sub>		4.5			I <sub>C</sub> = 2.1 mA	
			9			$I_{\rm C} = 3  \text{mA}$	
			17.5			$I_{\rm C} = 6  \text{mA}$	
			19.5			I <sub>C</sub> = 10 mA	

 $<sup>^{1}</sup>$  OP<sub>1dB</sub> is the output compression point achieved in a 50 Ω application circuit according to **Figure 1** using the integrated biasing.

 $I_{Cq}$  is the quiescent current at small input power levels.  $I_{Cq}$  increases up to  $I_{Ccomp}$  as RF input power approaches  $IP_{1dB}$ , cf. *Figure 14*.

### General purpose LNA MMIC with integrated ESD protection and active biasing



Table 12 AC characteristics,  $V_C = 3 \text{ V}, f = 3.5 \text{ GHz}$ 

Parameter	Symbol	Values			Unit	Note or test conditions
		Min.	Тур.	Мах.		
Minimum noise figure	NF <sub>min</sub>	_	0.8	_	dB	I <sub>C</sub> = 2.1 mA
			0.75			$I_{\rm C} = 3  \text{mA}$
			0.7			$I_{\rm C} = 6  \text{mA}$
			0.75			I <sub>C</sub> = 10 mA
Transducer gain	$ S_{21} ^2$		13.5			I <sub>C</sub> = 2.1 mA
			15.5			$I_{\rm C} = 3  \text{mA}$
			18			$I_C = 6 \text{ mA}$
			19			$I_{\rm C} = 10  {\rm mA}$
Maximum power gain	$G_{ms}$		18.5			$I_{\rm C} = 2.1  {\rm mA}$
			20			$I_C = 3 \text{ mA}$
			22			$I_{C} = 6 \text{ mA}$
			23.5			$I_{\rm C} = 10  {\rm mA}$
Output 1 dB gain compression point <sup>1)</sup>	OP <sub>1dB</sub>		10		dBm	$I_{Cq} = 2.1 \text{ mA}, I_{Ccomp} = 16 \text{ mA}$
			10			$I_{Cq} = 3 \text{ mA}, I_{Ccomp} = 16 \text{ mA}$
			9			$I_{Cq} = 6 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$
			8			$I_{Cq} = 10 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$
Output 3 <sup>rd</sup> order intercept point	OIP <sub>3</sub>		5.5			I <sub>C</sub> = 2.1 mA
			12			$I_{\rm C} = 3  \text{mA}$
			17.5			$I_{\rm C} = 6  \text{mA}$
			19			I <sub>C</sub> = 10 mA

 $<sup>^{1}</sup>$  OP<sub>1dB</sub> is the output compression point achieved in a 50 Ω application circuit according to **Figure 1** using the integrated biasing.

 $I_{Cq}$  is the quiescent current at small input power levels.  $I_{Cq}$  increases up to  $I_{Ccomp}$  as RF input power approaches  $IP_{1dB}$ , cf. *Figure 14*.

### General purpose LNA MMIC with integrated ESD protection and active biasing



Table 13 AC characteristics,  $V_C = 3 \text{ V}, f = 5.5 \text{ GHz}$ 

Parameter	Symbol	Values			Unit	Note or test conditions
		Min.	Тур.	Мах.		
Minimum noise figure	NF <sub>min</sub>	_	1.05	_	dB	I <sub>C</sub> = 2.1 mA
			1			$I_{\rm C} = 3  \text{mA}$
			0.9			$I_{C} = 6 \text{ mA}$
			0.95			$I_{\rm C}$ = 10 mA
Transducer gain	$ S_{21} ^2$		11.5			I <sub>C</sub> = 2.1 mA
			13			$I_{\rm C} = 3  \text{mA}$
			15			$I_{\rm C}$ = 6 mA
			15.5			$I_{\rm C}$ = 10 mA
Maximum power gain	G <sub>ms</sub>		17.5			I <sub>C</sub> = 2.1 mA
			18.5			$I_{\rm C} = 3  \text{mA}$
			20			$I_C = 6 \text{ mA}$
			19			$I_{\rm C}$ = 10 mA
Output 1 dB gain compression point 1)	OP <sub>1dB</sub>		10.5		dBm	$I_{Cq} = 2.1 \text{ mA}, I_{Ccomp} = 17 \text{ mA}$
			10			$I_{Cq} = 3 \text{ mA}, I_{Ccomp} = 17 \text{ mA}$
			9			$I_{Cq} = 6 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$
			8			$I_{Cq} = 10 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$
Output 3 <sup>rd</sup> order intercept point	OIP <sub>3</sub>		6.5			I <sub>C</sub> = 2.1 mA
			12			$I_{\rm C} = 3  \text{mA}$
			22			$I_{\rm C} = 6  \text{mA}$
			21			I <sub>C</sub> = 10 mA

 $<sup>^{1}</sup>$  OP<sub>1dB</sub> is the output compression point achieved in a 50 Ω application circuit according to **Figure 1** using the integrated biasing.

 $I_{Cq}$  is the quiescent current at small input power levels.  $I_{Cq}$  increases up to  $I_{Ccomp}$  as RF input power approaches  $IP_{1dB}$ , cf. *Figure 14*.

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Table 14 AC characteristics,  $V_C = 3 \text{ V}$ , f = 10 GHz

Parameter	Symbol	Values			Unit	Note or test conditions
		Min.	Тур.	Мах.		
Minimum noise figure	NF <sub>min</sub>	_	2	_	dB	I <sub>C</sub> = 2.1 mA
			1.8			$I_{\rm C} = 3  \text{mA}$
			1.5			$I_C = 6 \text{ mA}$
			1.5			$I_{\rm C}$ = 10 mA
Transducer gain	$ S_{21} ^2$		5.5			I <sub>C</sub> = 2.1 mA
			7			$I_{\rm C} = 3  \text{mA}$
			9			$I_{C} = 6 \text{ mA}$
			10			$I_{\rm C} = 10  {\rm mA}$
Maximum power gain	G <sub>ms</sub>		14.5			I <sub>C</sub> = 2.1 mA
			15			$I_{\rm C} = 3  \text{mA}$
			15.5			$I_C = 6 \text{ mA}$
			15.5			$I_{\rm C} = 10  {\rm mA}$
Output 1 dB gain compression point <sup>1)</sup>	OP <sub>1dB</sub>		6		dBm	$I_{Cq} = 2.1 \text{ mA}, I_{Ccomp} = 16 \text{ mA}$
			6			$I_{Cq} = 3 \text{ mA}, I_{Ccomp} = 16 \text{ mA}$
			4			$I_{Cq} = 6 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$
			4			$I_{Cq} = 10 \text{ mA}, I_{Ccomp} = 15 \text{ mA}$
Output 3 <sup>rd</sup> order intercept point	OIP <sub>3</sub>		2.5			I <sub>C</sub> = 2.1 mA
			7			$I_{\rm C} = 3  \text{mA}$
			19.5			$I_{\rm C} = 6  \text{mA}$
			18			I <sub>C</sub> = 10 mA

 $<sup>^{1}</sup>$  OP<sub>1dB</sub> is the output compression point achieved in a 50 Ω application circuit according to **Figure 1** using the integrated biasing.

 $I_{Cq}$  is the quiescent current at small input power levels.  $I_{Cq}$  increases up to  $I_{Ccomp}$  as RF input power approaches  $IP_{1dB}$ , cf. *Figure 14*.



**Electrical characteristics** 

## 4.3.2 Typical AC characteristic curves

Measurement setup is as described in *Figure 7* except for *Figure 14*, where the compression point is measured in a 50  $\Omega$  application circuit according to *Figure 1* using the integrated biasing at  $V_C = 3 \text{ V}$ ,  $T_A = 25 \text{ °C}$ .

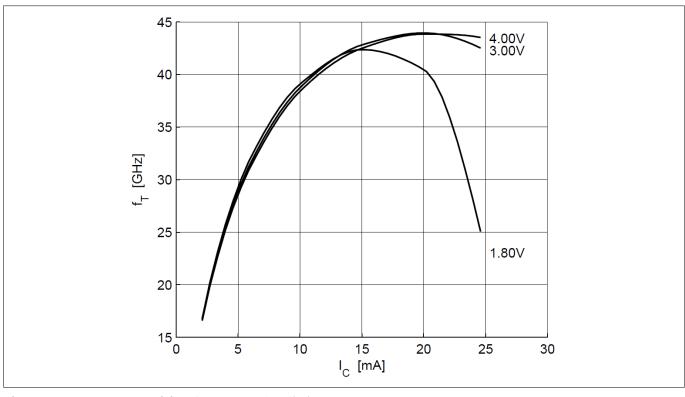


Figure 8 Transition frequency  $f_T = f(I_C)$ ,  $V_C =$  parameter

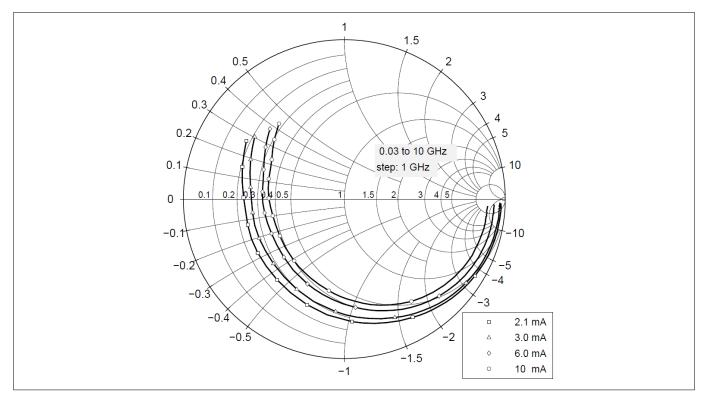


Figure 9 Input reflection coefficient  $S_{11} = f(f)$ ,  $I_C =$  parameter



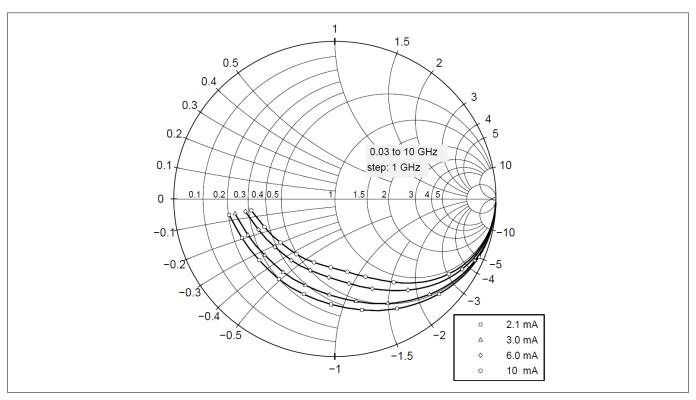


Figure 10 Output reflection coefficient  $S_{22} = f(f)$ ,  $I_C =$  parameter

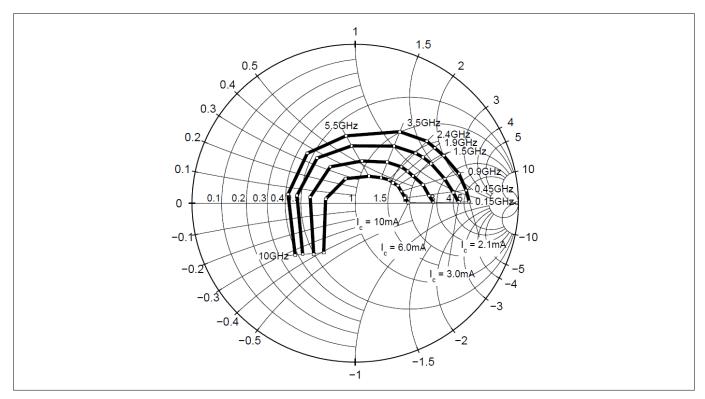


Figure 11 Source impedance for minimum noise figure  $Z_{S,opt} = f(f)$ ,  $I_C = parameter$ 

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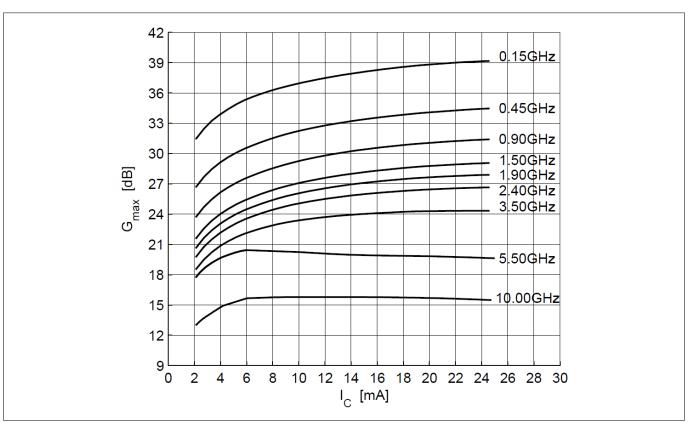


Figure 12 Maximum power gain  $G_{\text{max}} = f(I_{\text{C}}), f = \text{parameter}$ 

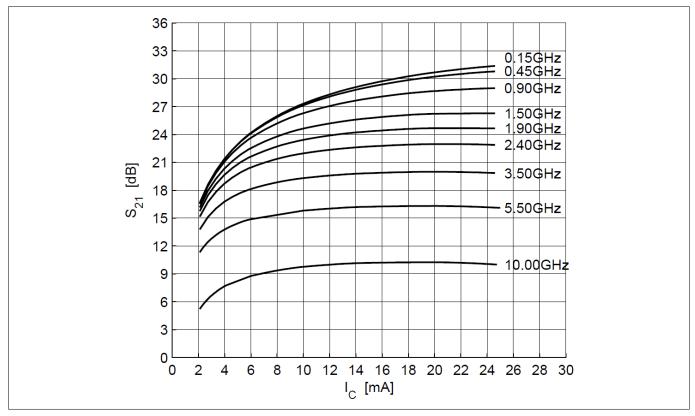


Figure 13 Transducer gain  $|S_{21}|^2 = f(I_C)$ , f = parameter



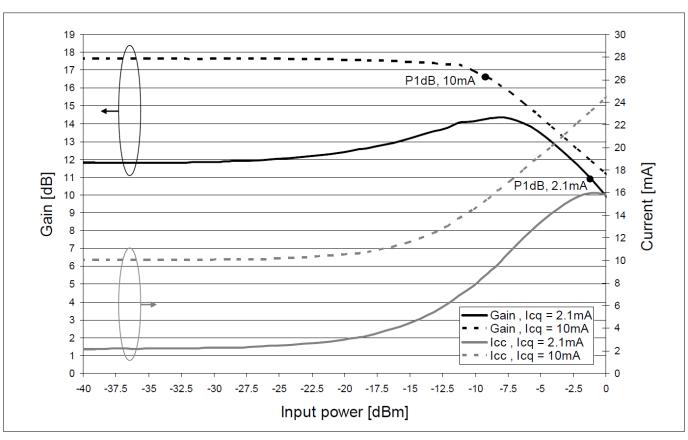


Figure 14 Power gain  $G = f(P_{RFin})$  and supply current  $I_{cc} = f(P_{RFin})$  at frequency f = 3.5 GHz,  $I_{cq} = parameter$ 

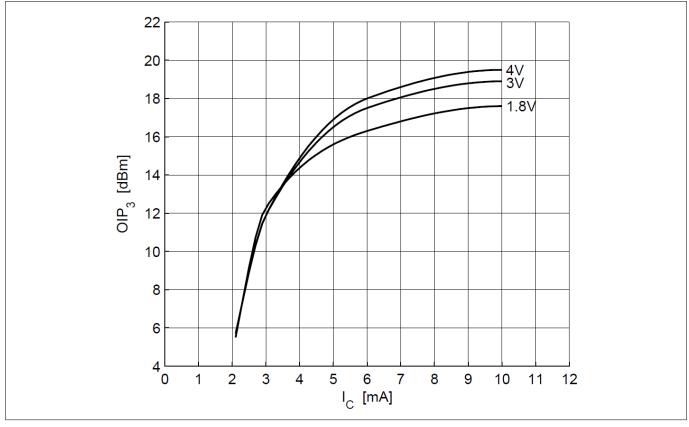


Figure 15 Output  $3^{rd}$  order intercept point  $OIP_3 = f(I_C)$  at frequency f = 3.5 GHz,  $V_C =$  parameter



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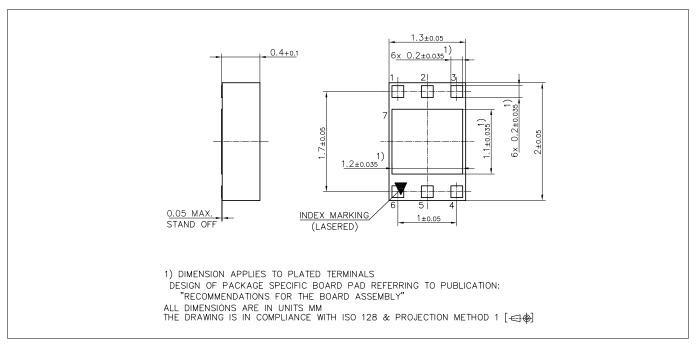


Figure 16 Package outline

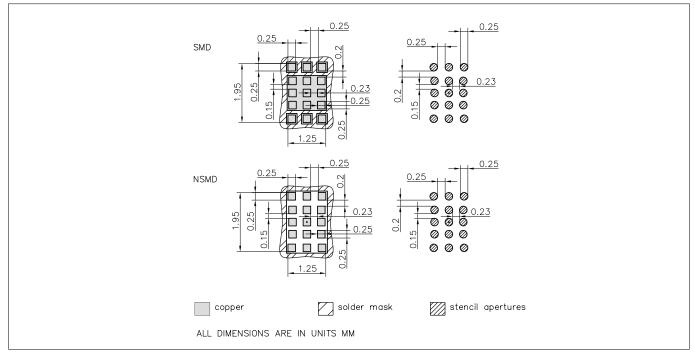


Figure 17 Foot print

### General purpose LNA MMIC with integrated ESD protection and active biasing



### Package information TSLP-7-1

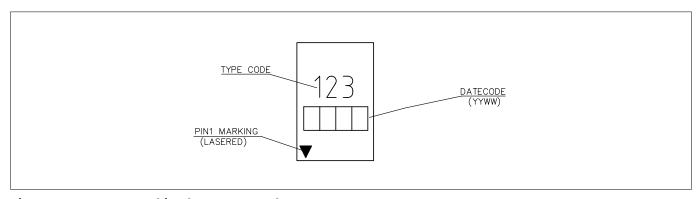


Figure 18 Marking layout example

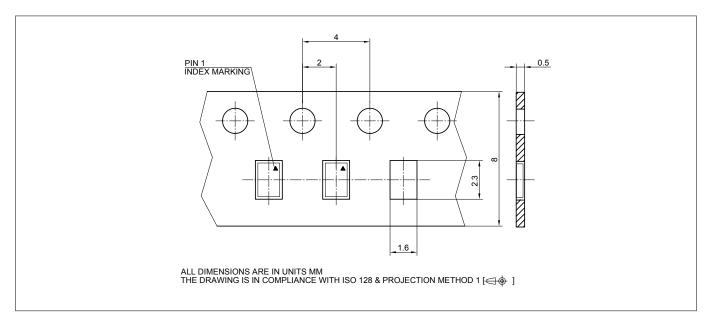


Figure 19 Tape information

Note: See our Recommendations for Printed Circuit Board Assembly of TSLP/TSSLP/TSNP Packages.

The marking layout is an example. For the real marking code refer to the device information on the first page. The number of characters shown in the layout example is not necessarily the real one. The marking layout can consist of less characters.

## General purpose LNA MMIC with integrated ESD protection and active biasing



**Revision history** 

# **Revision history**

Document version	Date of release	Description of changes
4.0	2018-09-26	New datasheet layout.

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